

INTERNATIONAL STANDARD

**Semiconductor devices - Mechanical and climatic test methods -
Part 24: Accelerated moisture resistance - Unbiased HAST**

(<https://standards.iteh.ai>)

Document Preview

[IEC 60749-24:2025](https://standards.iteh.ai/catalog/standards/iec/c97118fa-a4aa-4d57-b9c7-6eb7e9a48a33/iec-60749-24-2025)

<https://standards.iteh.ai/catalog/standards/iec/c97118fa-a4aa-4d57-b9c7-6eb7e9a48a33/iec-60749-24-2025>



THIS PUBLICATION IS COPYRIGHT PROTECTED
Copyright © 2025 IEC, Geneva, Switzerland

All rights reserved. Unless otherwise specified, no part of this publication may be reproduced or utilized in any form or by any means, electronic or mechanical, including photocopying and microfilm, without permission in writing from either IEC or IEC's member National Committee in the country of the requester. If you have any questions about IEC copyright or have an enquiry about obtaining additional rights to this publication, please contact the address below or your local IEC member National Committee for further information.

IEC Secretariat
3, rue de Varembe
CH-1211 Geneva 20
Switzerland

Tel.: +41 22 919 02 11
info@iec.ch
www.iec.ch

About the IEC

The International Electrotechnical Commission (IEC) is the leading global organization that prepares and publishes International Standards for all electrical, electronic and related technologies.

About IEC publications

The technical content of IEC publications is kept under constant review by the IEC. Please make sure that you have the latest edition, a corrigendum or an amendment might have been published.

IEC publications search -

webstore.iec.ch/advsearchform

The advanced search enables to find IEC publications by a variety of criteria (reference number, text, technical committee, ...). It also gives information on projects, replaced and withdrawn publications.

IEC Just Published - webstore.iec.ch/justpublished

Stay up to date on all new IEC publications. Just Published details all new publications released. Available online and once a month by email.

IEC Customer Service Centre - webstore.iec.ch/csc

If you wish to give us your feedback on this publication or need further assistance, please contact the Customer Service Centre: sales@iec.ch.

IEC Products & Services Portal - products.iec.ch

Discover our powerful search engine and read freely all the publications previews, graphical symbols and the glossary. With a subscription you will always have access to up to date content tailored to your needs.

Electropedia - www.electropedia.org

The world's leading online dictionary on electrotechnology, containing more than 22 500 terminological entries in English and French, with equivalent terms in 25 additional languages. Also known as the International Electrotechnical Vocabulary (IEV) online.

[IEC 60749-24:2025](https://standards.iteh.ai/catalog/standards/iec/c97118fa-a4aa-4d57-b9c7-6eb7e9a48a33/iec-60749-24-2025)

<https://standards.iteh.ai/catalog/standards/iec/c97118fa-a4aa-4d57-b9c7-6eb7e9a48a33/iec-60749-24-2025>

Warning! Make sure that you obtained this publication from an authorized distributor.

CONTENTS

FOREWORD	2
1 Scope	4
2 Normative references	4
3 Terms and definitions	4
4 Test requirements	4
5 Test apparatus	5
5.1 Test chamber	5
5.2 Records	5
5.3 Devices under stress	5
5.4 Ionic contamination	5
5.5 Distilled or deionized water	5
6 Test conditions	5
7 Procedure	6
7.1 Mounting	6
7.2 Ramp-up	6
7.3 Ramp-down	7
7.4 Test clock	7
7.5 Electrical tests	7
7.6 Handling	7
8 Failure criteria	7
9 Safety	7
10 Summary	8
Bibliography	9
Table 1 – Test conditions for accelerated moisture resistance testing	6

<https://standards.iteh.ai/catalog/standards/iec/c97118fa-a4aa-4d57-b9c7-6eb7e9a48a33/iec-60749-24-2025>